


| | | |
|--|--|---|
| Search Notes  | Application/Control No. 10574286 | Applicant(s)/Patent Under Reexamination OIKAWA ET AL. |
| | Examiner CEDRIC CHAN | Art Unit 1773 |

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|---------------------------------|------------|----------|
| 422 | 99,102,104,255,261,266,292 | 12/16/2010 | CC |
| 134 | 73,75,82,83,85,92,104.1,117,165 | 12/16/2010 | CC |
| 216 | 83,84,100,8,10 | 12/16/2010 | CC |
| 118 | 400,404,421,427 | 12/16/2010 | CC |
| 422 | 500,547,566,300,301 | 3/20/2011 | CC |

SEARCH NOTES

| Search Notes | Date | Examiner |
|--|------------|----------|
| inventor name search (PALM) | 2/5/2010 | CC |
| inventor name search (EAST) | 2/13/2010 | CC |
| searched US/Foreign databases -- EAST/USPat,OCR,PGPub,EPO,JPO,Derwent | 2/13/2010 | CC |
| assignee search (EAST) | 8/21/2010 | CC |
| updated class, inventor search & updated keyword search of US/For databases (see EAST History) | 8/21/2010 | CC |
| updated inventor/assignee search w/ lim text in EAST; updated keyword search | 12/16/2010 | CC |
| updated classification search, additionally searched new subclasses in class 134 and 118 | 12/16/2010 | CC |
| Interference search (see EAST Search History, attached) | 12/16/2010 | CC |
| updated 422 class search | 3/20/2011 | CC |

INTERFERENCE SEARCH

| Class | Subclass | Date | Examiner |
|-------|----------------|------------|----------|
| 422 | 99,102,104,292 | 12/16/2010 | CC |
| 134 | 104.1,117 | 12/16/2010 | CC |
| 118 | 404,421 | 12/16/2010 | CC |

/C. C. /
Examiner, Art Unit 1773